

4/17/2013



**RELIABILITY MONITOR REPORT
FOR**

MFN Poly Emitter Complementary Bipolar (CB50)

MAXIM INTEGRATED

**160 RIO ROBLES
SAN JOSE, CA 95134**

**This Report was prepared by
MAXIM INTEGRATED Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX3646ETG+	MAX3738ETG+	MAX3747AEUB	MAX3747BEUB
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The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 16730 QUANTITY: 194 FAILS: 0 FITS: 6.8

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2012 and 3/31/2013 .

Process Information:

Process Description: MFN Poly Emitter Complementary Bipolar (CB50)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1231	MAX3738ETG+	135°C	500 HRS	80	0	JJR1A2059KA
HIGH TEMP OP LIFE	1238	MAX3747BEUB+	135°C	500 HRS	34	0	JHDYC2047L
HIGH TEMP OP LIFE	1247	MAX3738ETG+	135°C	500 HRS	80	0	JJR1A3092BA
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1152	MAX3646ETG+	-65C TO 150C	1000 CYS	77	0	JJR0J3056BC
TEMP CYCLE, 5' RAMP, 10' DWELL	1152	MAX3646ETG+	-65C TO 150C	1000 CYS	77	0	JJR0J3056BA
TEMP CYCLE, 5' RAMP, 10' DWELL	1208	MAX3646ETG+	-65C TO 150C	1000 CYS	77	0	JJR0J3046
TEMP CYCLE, 5' RAMP, 10' DWELL	1208	MAX3646ETG+	-65C TO 150C	1000 CYS	77	0	JJR0J3046BA
TEMP CYCLE, 5' RAMP, 10' DWELL	1214	MAX3747AEUB+	-65C TO 150C	1000 CYS	77	0	JHDZE3015BB
TEMP CYCLE, 5' RAMP, 10' DWELL	1214	MAX3747AEUB+	-65C TO 150C	1000 CYS	77	0	JHDZE3015BA
Total:						0	

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